

## PATENT APPLICATION

Sheet 2 of 2

FORM PTO-1449  LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT  (Use sev ral sheets if necessary)	ATTY. DOCKET NO. <b>10970792-4</b>	APPLICATION NO. <b>10/723,891</b>	CONFIRMATION NO.
	APPLICANT <b>Melissa D. Boyd et al.</b>		
	FILING DATE <b>Herewith</b>	GROUP <b>Unkn.</b>	

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	2A	5,097,275	03/1992	Takita	
	2B	5,561,448	10/1996	Kaneko et al.	
	2C				
	2D				
	2E				
	2F				
	2G				
	2H				
	2I				
	2J				
	2K				

KS  
02/26/04

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	2L					
	2M					
	2N					
	2O					
	2P					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	2Q	*Multilayered Focal Plane Structures With Self-Aligning Detector Assembly*; David E. Ludwig; SPIE; Vol. 2745; 1996; pgs: 149-158.
	2R	*Experimental Results On The Self-Alignment Process Using Au/Sn Metallurgy And On The Growth Of The S-Phase During The Reflow*; Christine Kallmayer, et al; 1995; Semiconductor Technology Center, Inc-Symposium; pgs 225-237.
	2S	*Photolithography In Anisotropically Etched Grooves*; S. Linder, et al.; 1996; IEEE; pgs. 38-43.

EXAMINER

DATE CONSIDERED

9/13/04